

Silicon N-Channel Power MOSFET

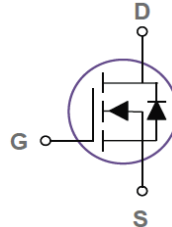
Preliminary

Features

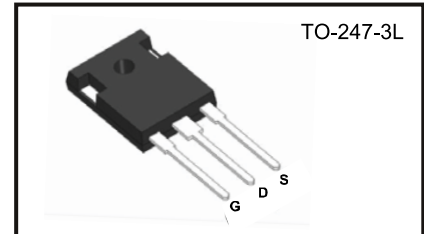
- Fast Switching
- Low On-Resistance
- Low Gate Charge Minimize Switching Loss
- Low Reverse Transfer Capacitances
- 100% Single Pulse Avalanche Energy Test

Applications

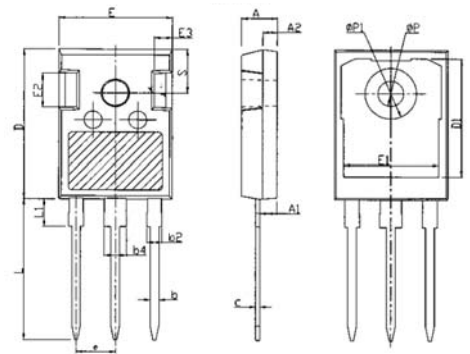
- Power Switch Circuit of Adaptor and Charger



V_{DSS}	900V
$I_D(@25^{\circ}C)$	9A
$R_{DS(ON) \text{ max.}}$	1.4 Ω



Package Dimensions



Absolute Maximum Ratings

($T_C = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Ratings	Unit
Drain Source Voltage	V_{DSS}	900	V
Gate Source Voltage	V_{GS}	± 30	V
Drain Current Continuous	I_D	9 5.8	A
		@ $T_C = 25^{\circ}C$ @ $T_C = 100^{\circ}C$	
Drain Current Pulsed	I_{DM}	36	A
		Note 1	
Single Pulse Avalanche Energy	E_{AS}	580	mJ
		Note 2	
Avalanche Energy ,Repetitive	E_{AR}	58	mJ
		Note 1	
Avalanche Current	I_{AR}	3.4	A
		Note 1	
Peak Diode Recovery dv/dt @ $T_C = 25^{\circ}C$	dv/dt	5.0	V/ns
		Note 3	
Power Dissipation	P_D	240	W
Storage Temperature Range	T_{STG}	-55 to +150	$^{\circ}C$
Operating Junction Temperature Range	T_J	-55 to +150	$^{\circ}C$
Thermal Resistance Junction to Case	$R_{\theta JC}$	typ. 0.41 max. 0.52	$^{\circ}C/W$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62	$^{\circ}C/W$

*Caution stresses greater than those in the "Absolute Maximum. Ratings" may cause permanent damage to the device.

Note : 1. Repetitive rating pulse width limited by maximum junction temperature

2. $L = 10mH, I_D = 10.8A, \text{Start } T_J = 25^{\circ}C$

3. $I_{SD} = 9A, di/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}, \text{Start } T_J = 25^{\circ}C$

UNIT:mm			
Symbol	Min.	Nom	Max.
A	4.80	5.00	5.20
A1	2.21	2.41	2.61
A2	1.85	2.00	2.15
b	1.11	1.21	1.36
b2	1.91	2.01	2.21
b4	2.91	3.01	3.21
c	0.51	0.61	0.75
D	20.70	21.00	21.30
D1	16.25	16.55	16.85
E	15.50	15.80	16.10
E1	13.00	13.30	13.60
E2	4.80	5.00	5.20
E3	2.30	2.50	2.70
e	5.44BSC		
L	19.62	19.92	20.22
L1	-	-	4.30
ϕP	3.40	3.60	3.80
$\phi P1$	-	-	7.30
S	6.15BSC		

Electrical Characteristics @ $T_c = 25^\circ\text{C}$ (unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
OFF Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=0.25mA$	900	-	-	V
Drain-Source Leakage Current	I_{DSS}	$V_{GS}=0V, V_{DS}=900V, T_a=25^\circ\text{C}$	-	-	1	μA
Gate To Source Leakage Current	I_{GSS}	$V_{GS}=\pm 30V, V_{DS}=0V$	-	-	± 100	nA
ON Characteristics (Pulse Width < 380μs, Duty Cycle < 2%.)						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=0.25mA$	2.0	-	4.0	V
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=4.5A$	-	-	1.4	Ω
Forward Transconductance	g_{fs}	$V_{DS}=30V, I_D=4.5A$	-	9.2	-	S
Dynamic Characteristics						
Input Capacitance	C_{iss}	$V_{DS}=25V$	-	2593	-	pF
Output Capacitance	C_{oss}	$V_{GS}=0V$	-	146	-	
Reverse Transfer Capacitance	C_{rss}	Freq.=1MHz	-	30	-	
Switching Characteristics						
Turn-On Delay Time	$t_{d(on)}$	$V_{DD}=450V$	-	35	-	ns
Rise Time	t_r	$V_{GS}=10V$	-	41	-	
Turn-Off Delay Time	$t_{d(off)}$	$I_D=9A$	-	134	-	
Fall Time	t_f	$R_G=12\Omega$	-	45	-	
Total Gate Charge	Q_g	$V_{DS}=400V$	-	49	-	nC
Gate to Source Charge	Q_{gs}	$V_{GS}=10V$	-	13	-	
Gate to Drain Charge	Q_{gd}	$I_{DS}=9A$	-	17	-	
Source-Drain Diode Characteristics						
Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_S=9A$	-	-	1.5	V
Continuous Source Current (Body Diode)	I_{SD}		-	-	9	A
Max. Pulsed Current (Body Diode)	I_{SM}		-	-	36	A
Reverse Recovery Time	T_{rr}	$V_{GS}=0V$ $I_S=9A, T_J=25^\circ\text{C}$	-	562	-	ns
Reverse Recovery Charge	Q_{rr}	$di/dt=100A/\mu\text{s}$	-	3.5	-	μC

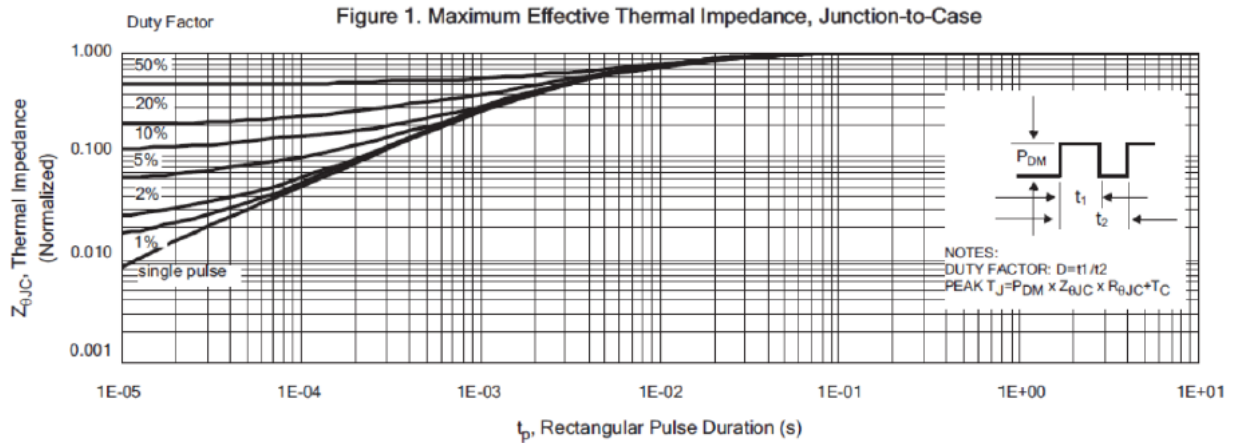
Typical Performance Characteristics


Figure 2. Maximum Power Dissipation vs Case Temperature

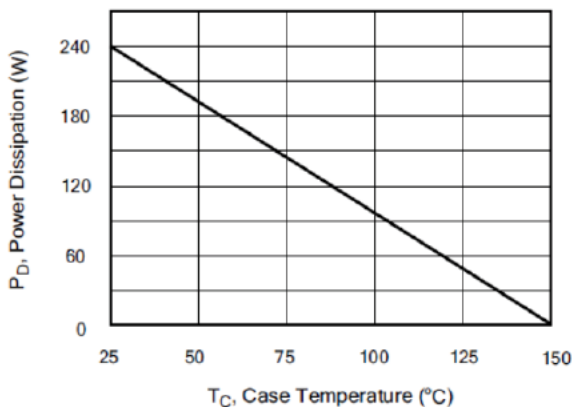


Figure 3. Maximum Continuous Drain Current vs Case Temperature

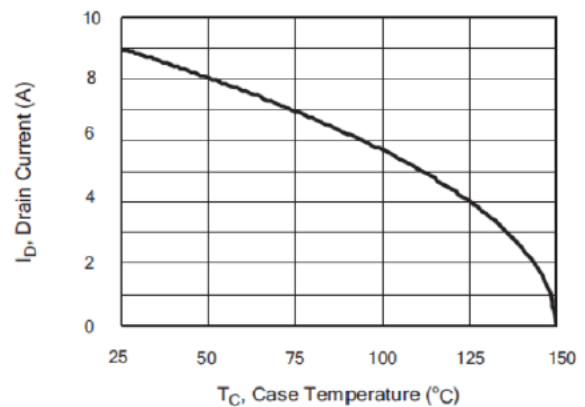


Figure 4. Typical Output Characteristics

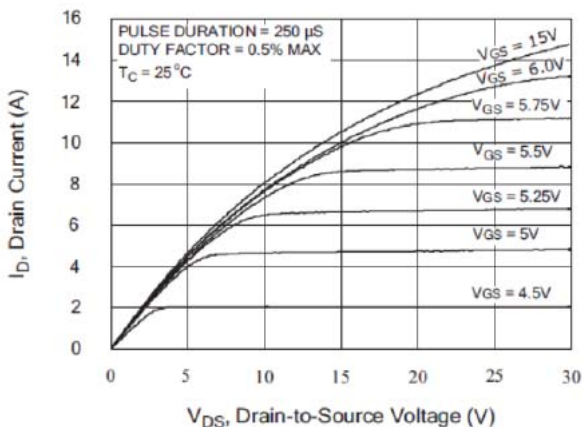
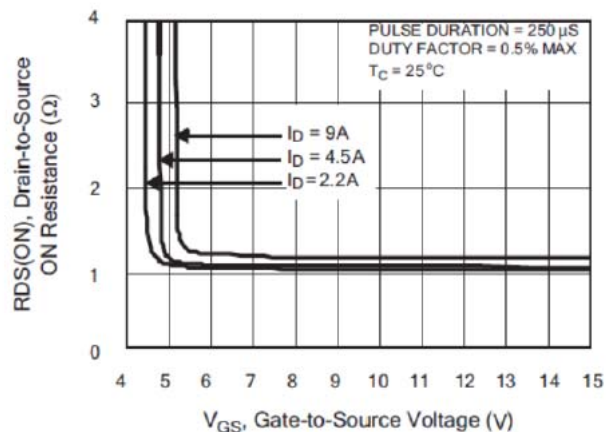
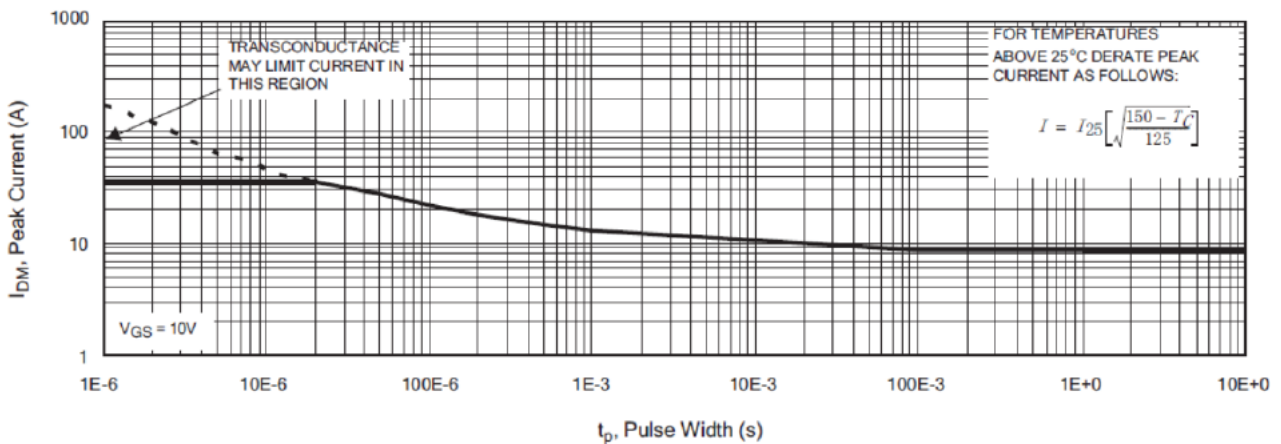
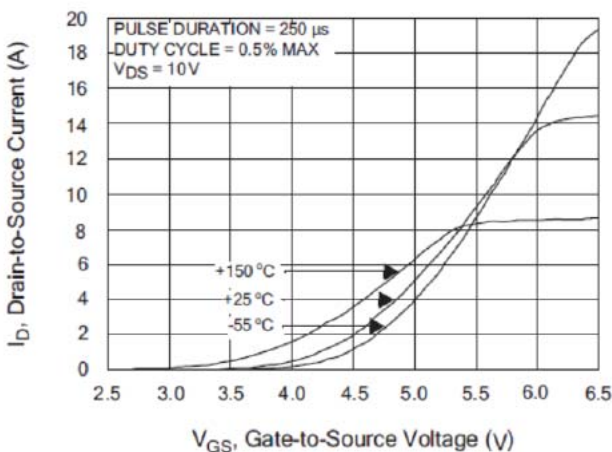
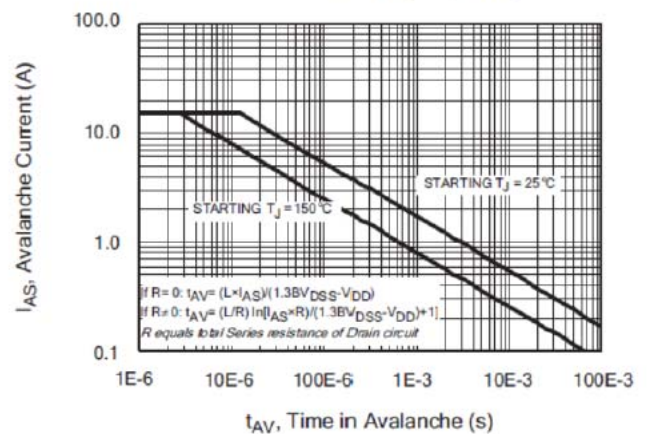
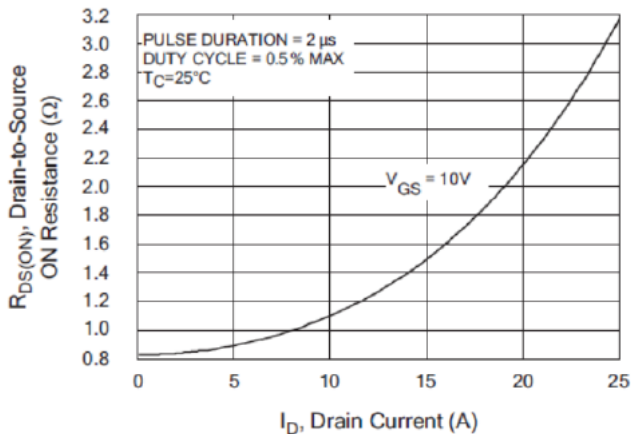
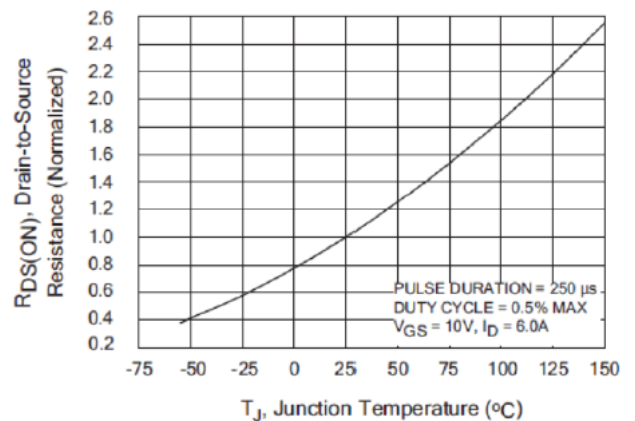
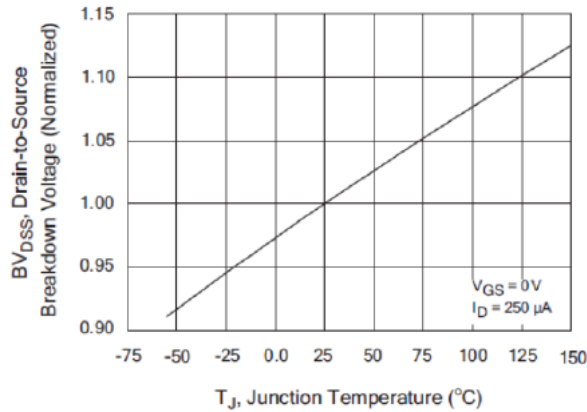
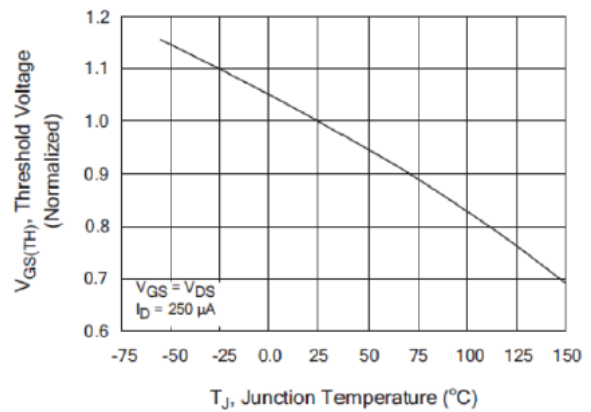
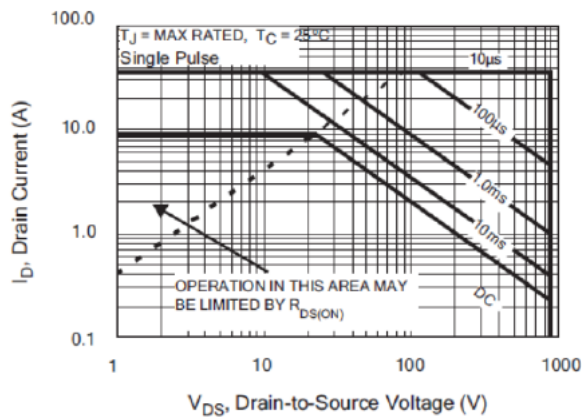
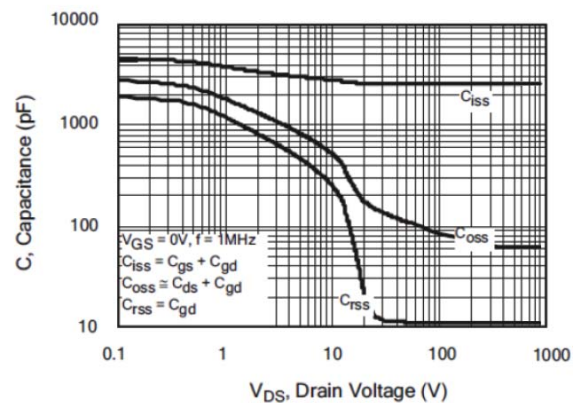
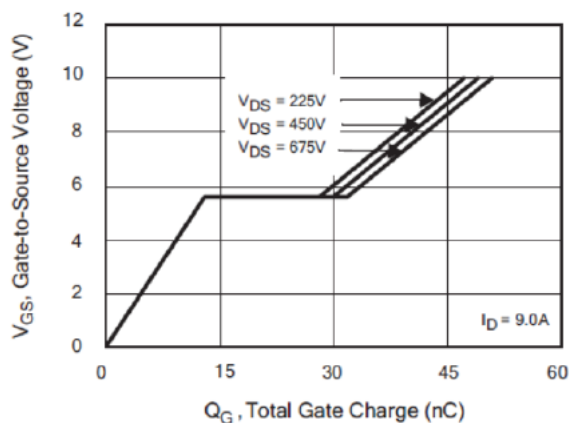
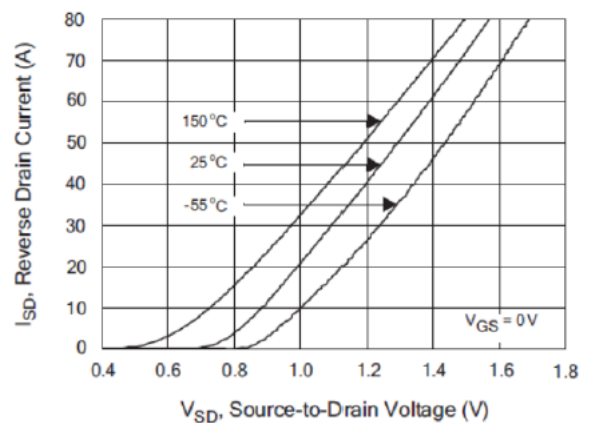


Figure 5. Typical Drain-to-Source ON Resistance vs Gate Voltage and Drain Current



Typical Performance Characteristics
Figure 6. Maximum Peak Current Capability

Figure 7. Typical Transfer Characteristics

Figure 8. Unclamped Inductive Switching Capability

Figure 9. Typical Drain-to-Source ON Resistance vs Drain Current

Figure 10. Typical Drain-to-Source ON Resistance vs Junction Temperature


Typical Performance Characteristics
Figure 11. Typical Breakdown Voltage vs Junction Temperature

Figure 12. Typical Threshold Voltage vs Junction Temperature

Figure 13. Maximum Forward Bias Safe Operating Area

Figure 14. Typical Capacitance vs Drain-to-Source Voltage

Figure 15. Typical Gate Charge vs Gate-to-Source Voltage

Figure 16. Typical Body Diode Transfer Characteristics


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